











TS3A5018 SCDS189H-JANUARY 2005-REVISED MAY 2018

TS3A5018 10-Ω Quad SPDT Analog Switch

Features

- Low ON-State Resistance (10 Ω)
- Low Charge Injection
- **Excellent ON-State Resistance Matching**
- Low Total Harmonic Distortion (THD)
- 1.8-V to 3.6-V Single-Supply Operation
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Performance Tested Per JESD 22
 - 2000-V Human-Body Mode (A114-B, Class II)
 - 1000-V Charged-Device Model (C101)

Applications

- Sample-and-Hold Circuits
- **Battery-Powered Equipment**
- Audio and Video Signal Routing
- **Communication Circuits**

3 Description

The TS3A5018 device is a quad single-pole doublethrow (SPDT) analog switch that is designed to operate from 1.8 V to 3.6 V. This device can handle digital and analog signals, and signals up to V₊ can be transmitted in either direction.

Device Information⁽¹⁾

_		= = -
PART NUMBER	PACKAGE	BODY SIZE (NOM)
	SOIC (16)	9.90 mm × 6.00 mm
	SSOP (16)	6.00 mm × 4.90 mm
TS3A5018	TSSOP (16)	5.00 mm × 4.40 mm
133A3016	TVSOP (16)	4.40 mm × 3.60 mm
	UQFN (16)	2.50 mm × 1.80 mm
	VQFN (16)	4.00 mm × 3.50 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Block Diagram

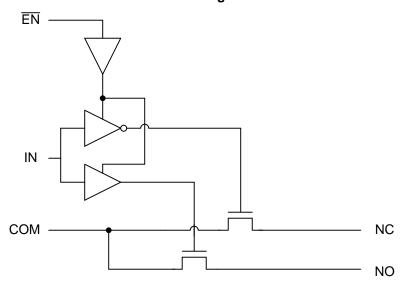




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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Cr	nanges from Revision G (March 2015) to Revision H	Page
•	Changed the pinout images	3
•	Changed the r_{on} MAX value at 25°C From: 8 Ω To: 17 Ω in the <i>Electrical Characteristics for 1.8-V Supply</i> table	7
•	Changed the r_{on} MAX value at Full From: 14.55 Ω To: 32 Ω in the <i>Electrical Characteristics for 1.8-V Supply</i> table	7
_	Changed the 1 ₀₀ MAX value at 1 till 1 1011. 14.33 12 10. 32 12 iii the Electrical Characteristics for 1.5-V Supply table	-

Changes from Revision F (June 2013) to Revision G

Page

- Added Applications, Device Information table, Pin Functions table, ESD Ratings table, Thermal Information table,
 Typical Characteristics, Feature Description section, Device Functional Modes, Application and Implementation
 section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and
 Mechanical, Packaging, and Orderable Information section.
- Deleted Ordering Information table.

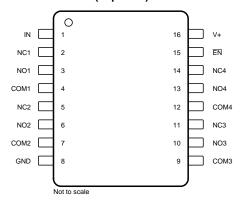
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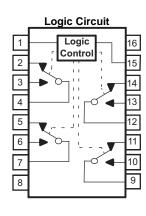
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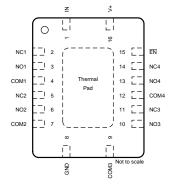
5 Pin Configuration and Functions

D, DBQ, DGV and PW Package 16-Pin SOIC, SSOP, TVSOP and TSSOP (Top View)

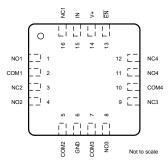




RGY Package 16-Pin VQFN (Top View)







Pin Functions

	PIN							
NAME	SOIC, SSOP, TVSOP, VQFN NO.	UQFN NO.	TYPE	DESCRIPTION				
COM1	4	2	I/O	Common path for switch				
COM2	7	5	I/O	Common path for switch				
COM3	9	7	I/O	Common path for switch				
COM4	12	10	I/O	Common path for switch				
EN	15	13	1	Active-low switch enable input				
GND	8	6	_	Ground				
IN	1	15	ı	Switch path selector input				
NC1	2	16	I/O	Normally closed path for switch				
NC2	5	3	I/O	Normally closed path for switch				
NC3	11	9	I/O	Normally closed path for switch				
NC4	14	12	I/O	Normally closed path for switch				
NO1	3	1	I/O	Normally open path for switch				
NO2	6	4	I/O	Normally open path for switch				
NO3	10	8	I/O	Normally open path for switch				
NO4	13	11	I/O	Normally open path for switch				
V+	16	14	_	Supply voltage				



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)(2)

			MIN	MAX	UNIT
V ₊	Supply voltage ⁽³⁾		-0.5	4.6	V
V _{NC}					
V_{NO}	Analog voltage (3) (4)		-0.5	4.6	V
V_{COM}					
I _K	Analog port diode current	V _{NC} , V _{NO} , V _{COM} < 0	-50		mA
I _{NC}					
I_{NO}	ON-state switch current	V_{NC} , V_{NO} , $V_{COM} = 0$ to 7 V	-64	64	mA
I_{COM}					
VI	Digital input voltage (3)(4)		-0.5	4.6	V
I _{IK}	Digital input clamp current	V _I < 0	-50		mA
I ₊	Continuous current through V ₊		-100	100	mA
I _{GND}	Continuous current through GND		-100	100	mA
T _{stg}	Storage temperature		-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
		Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	±2000	
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±1000	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
V _{I/O}	Switch input and output voltage	0	V_{+}	V
V ₊	Supply voltage	1.65	3.6	V
VI	Control input voltage	0	3.6	V
T _A	Operating temperature	-40	85	°C

6.4 Thermal Information

•										
			TS3A5018							
THERMAL METRIC ⁽¹⁾		D (SOIC)	DBQ (SSOP)	DGV (TVSOP)	PW (TSSOP)	RGY (VQFN)	RSV (UQFN)	UNIT		
		16 PINS	16 PINS	16 PINS	16 PINS	16 PINS	16 PINS			
R_{\thetaJA}	Junction-to-ambient thermal resistance	73	90	120	108	51	184	°C/W		

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

⁽²⁾ The algebraic convention, whereby the most negative value is a minimum and the most positive value is a maximum

⁽³⁾ All voltages are with respect to ground, unless otherwise specified.

⁽⁴⁾ The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



6.5 Electrical Characteristics for 3.3-V Supply

 $V_{+} = 3 \text{ V to } 3.6 \text{ V}, T_{A} = -40^{\circ}\text{C to } 85^{\circ}\text{C (unless otherwise noted)}^{(1)}$

	PARAMETER	TEST CON	DITIONS	T _A	V ₊	MIN	TYP	MAX	UNIT
Analog Switch									
V _{COM} , V _{NO} , V _{NC}	Analog signal range					0		V_{+}	٧
	ON-state	$0 \le (V_{NC} \text{ or } V_{NO}) \le V_+,$	Switch ON,	25°C			7	10	
on	resistance	$I_{COM} = -32 \text{ mA},$	see Figure 17	Full	3 V			12	Ω
	ON-state	V_{NC} or $V_{NO} = 2.1 \text{ V}$,	Switch ON,	25°C			0.3	0.8	
∆r _{on}	resistance match between channels	$I_{COM} = -32 \text{ mA},$	see Figure 17	Full	3 V			1	Ω
	ON-state	$0 \le (V_{NC} \text{ or } V_{NO}) \le V_+,$	Switch ON,	25°C			5	7	
on(flat)	resistance flatness	$I_{COM} = -32 \text{ mA},$	see Figure 17	Full	3 V			8	Ω
		V _{NC} or V _{NO} = 1 V,		25°C		-0.1	0.05	0.1	
		$V_{COM} = 3 \text{ V},$ or V_{NC} or $V_{NO} = 3 \text{ V},$	Switch OFF, see Figure 18	Full	3.6 V	-0.2		0.2	
I _{NC(OFF)} ,	NC, NO	$V_{COM} = 1 \text{ V},$		2500		2	0.05	2	1 .
I _{NO(OFF)}	OFF leakage current	V_{NC} or $V_{NO} = 0$ to 3.6 V ,		25°C		-2	0.05	2	μΑ
		$V_{COM} = 3.6 \text{ V to } 0,$ or V_{NC} or $V_{NO} = 3.6 \text{ V to } 0,$	Switch OFF, see Figure 18	Full	0 V	-10		10	
		$V_{COM} = 0 \text{ to } 3.6 \text{ V},$							
		$V_{COM} = 1 \text{ V},$ $V_{NC} \text{ or } V_{NO} = 3 \text{ V},$ or	Switch OFF, see Figure 18	25°C	3.6 V	-0.1	0.05	0.1	
		$V_{COM} = 3 \text{ V},$ $V_{NC} \text{ or } V_{NO} = 3 \text{ V},$	555 T.Iguio 15	Full		-0.2		0.2	
COM(OFF)	COM OFF leakage current	V _{COM} = 0 to 3.6 V, V _{NC} or V _{NO} = 3.6 V to		25°C		-2	0.05	2	μΑ
		0, or V _{COM} = 3.6 V to 0, V _{NC} or V _{NO} = 0 to 3.6 V.	Switch OFF, see Figure 18	Full	ull 0 V	-10		10	
		V_{NC} or $V_{NO} = 1 V$,		25°C		-0.1	0.05	0.1	
NC(ON), NO(ON)	NC, NO ON leakage current	$V_{COM} = Open,$ or V_{NC} or $V_{NO} = 3 V,$ $V_{COM} = Open,$	Switch ON, see Figure 19	Full	3.6 V	-0.2		0.2	μΑ
		V _{COM} = 1 V,		25°C		-0.1	0.05	0.1	
COM(ON)	COM ON leakage current	V_{NC} or V_{NO} = Open, or V_{COM} = 3 V, V_{NC} or V_{NO} = Open,	Switch ON, see Figure 19	Full	3.6 V	-0.2		0.2	μΑ
V _{IH}	Input logic high			Full		2		V ₊	V
/ _{IL}	Input logic low			Full		0		0.8	V
I _{IH} , I _{IL}	Input leakage current	$V_1 = V_{\perp}$ or 0		25°C	3.6 V	-1	0.05	1	μA
'IH' 'IL	input leakage carrent	V = V ₊ 01 0		Full	3.0 V	-1		1	μ/ι
Q_{C}	Charge injection	$V_{GEN} = 0,$ $R_{GEN} = 0,$	$C_L = 0.1 \text{ nF},$ see Figure 26	25°C	3.3 V		2		pC
ONC(OFF),	NC, NO OFF capacitance	V_{NC} or $V_{NO} = V_{+}$ or GND,	Switch OFF, see Figure 20	25°C	3.3 V		4.5		pF
COM(OFF)	COM OFF capacitance	V _{COM} = V ₊ or GND,	Switch OFF, see Figure 20	25°C	3.3 V		9		pF
C _{NC(ON)} , C _{NO(ON)}	NC, NO ON capacitance	V_{NC} or $V_{NO} = V_{+}$ or GND,	Switch ON, see Figure 20	25°C	3.3 V		16		pF
C _{COM(ON)}	COM ON capacitance	$V_{COM} = V_{+} \text{ or GND},$	Switch ON, see Figure 20	25°C	3.3 V		16		pF

⁽¹⁾ The algebraic convention is used in this data sheet; the most negative value is shown in the minimum column.



Electrical Characteristics for 3.3-V Supply (continued)

 $V_{+} = 3 \text{ V to } 3.6 \text{ V}, T_{A} = -40^{\circ}\text{C to } 85^{\circ}\text{C (unless otherwise noted)}^{(1)}$

	PARAMETER	TEST C	ONDITIONS	TA	V ₊	MIN 7	ΥP	MAX	UNIT
Cı	Digital input capacitance	$V_I = V_+ \text{ or GND},$	See Figure 20	25°C	3.3 V		3		pF
BW	Bandwidth	$R_L = 50 \Omega$,	Switch ON, see Figure 22	25°C	3.3 V		300		MHz
O _{ISO}	OFF isolation	$R_L = 50 \Omega$, $f = 10 MHz$,	Switch OFF, see Figure 23	25°C	3.3 V		-48		dB
X _{TALK}	Crosstalk	$R_L = 50 \Omega$, $f = 10 MHz$,	Switch ON, see Figure 24	25°C	3.3 V		-48		dB
X _{TALK(ADJ)}	Crosstalk adjacent	$R_L = 50 \Omega$, $f = 10 MHz$,	Switch ON, see Figure 25	25°C	3.3 V		-81		dB
THD	Total harmonic distortion	$R_{L} = 600 \Omega,$ $C_{L} = 50 \text{ pF},$	f = 20 Hz to 20 kHz, see Figure 27	25°C	3.3 V	0.2	1%		
	Danish a summer of	V V OND	Oudtab ON OFF	25°C	0.01/		2.5	7	
1+	Positive supply current	$V_I = V_+ \text{ or GND},$	Switch ON or OFF	Full	3.6 V			10	μA

6.6 Electrical Characteristics for 2.5-V Supply

 $V_{+} = 2.3 \text{ V}$ to 2.7 V, $T_{A} = -40^{\circ}\text{C}$ to 85°C (unless otherwise noted)⁽¹⁾

	PARAMETER	TEST CO	NDITIONS	T _A	V ₊	MIN	TYP	MAX	UNIT
V_{COM}, V_{NC}, V_{NO}	Analog signal range					0		V_{+}	V
	ON-state	$0 \le (V_{NC} \text{ or } V_{NO}) \le V_+,$	Switch ON,	25°C	2.3 V		12	20	Ω
on	resistance	$I_{COM} = -24 \text{ mA},$	see Figure 17	Full	2.3 V			22	12
	ON-state	V_{NC} or $V_{NO} = 1.6 \text{ V}$,	Switch ON,	25°C	001/		0.3	1	0
∆r _{on}	resistance match between channels	$I_{COM} = -24 \text{ mA},$	see Figure 17	Full	2.3 V			2	Ω
	ON-state	$0 \le (V_{NC} \text{ or } V_{NO}) \le V_+,$	Switch ON,	25°C	0.01/		14	18	0
on(flat)	resistance flatness	$I_{COM} = -24 \text{ mA},$	see Figure 17	Full	2.3 V			20	Ω
		V_{NC} or $V_{NO} = 0.5 \text{ V}$,		25°C		-0.1	0.05	0.1	
NC(OFF)			Full	2.7 V	-0.2		0.2		
NO(OFF)				25°C		-2	0.05	2	μΑ
		or V_{NC} or $V_{NO} = 3.6 \text{ V to } 0$, see Figure 18	Full	0 V	-10		10		
	COM	V o V		25°C		-0.1	0.05	0.1	
			$\begin{split} &V_{NC} \text{ or } V_{NO} = 2.2 \text{ V,} \\ &\text{or} \\ &V_{COM} = 2.2 \text{ V,} \\ &V_{NC} \text{ or } V_{NO} = 0.5 \text{ V,} \end{split}$	Switch OFF, see Figure 18	Full	2.7 V	-0.2		0.2
COM(OFF)	OFF leakage current	$V_{COM} = 0 \text{ to } 3.6 \text{ V},$		25°C		-2	0.05	2	μΑ
	V _{NC} or V _{NO} = 3.6 V to 0, or V _{COM} = 3.6 V to 0, V _{NC} or V _{NO} = 0 to 3.6 V,	Full	0 V	-10		10			
		V_{NC} or $V_{NO} = 0.5 \text{ V}$,		25°C		-0.1	0.05	0.1	
NC(ON), NO(ON)	NC, NO ON leakage current	$\begin{aligned} &V_{COM} = Open, \\ ∨ \\ &V_{NC} \ or \ V_{NO} = 2.2 \ V, \\ &V_{COM} = Open, \end{aligned}$	Switch ON, see Figure 19	Full	Full 2.7 V	-0.2		0.2	μA
		$V_{COM} = 0.5 \text{ V},$		25°C		-0.1	0.05	0.1	
COM(ON)	COM ON leakage current	$\begin{split} &V_{NC} \text{ or } V_{NO} = \text{Open,} \\ &\text{ or } \\ &V_{COM} = 2.2 \text{ V,} \\ &V_{NC} \text{ or } V_{NO} = \text{Open,} \end{split}$	Switch ON, see Figure 19	Full	2.7 V	-0.2		0.2	μΑ
V _{IH}	Input logic high			Full		1.7		V ₊	V
V _{IL}	Input logic low			Full		0		0.7	V

(1) The algebraic convention is used in this data sheet; the most negative value is shown in the minimum column.



Electrical Characteristics for 2.5-V Supply (continued)

 $V_{+} = 2.3 \text{ V}$ to 2.7 V, $T_{A} = -40^{\circ}\text{C}$ to 85°C (unless otherwise noted)⁽¹⁾

	PARAMETER	TEST CON	NDITIONS	T _A	V ₊	MIN	TYP	MAX	UNIT
	Innut Ingles as aureant	\\ \\ a=0		25°C	2.7 V	-0.1	0.05	0.1	
I _{IH} , I _{IL}	Input leakage current	$V_1 = V_+ \text{ or } 0$		Full	2.7 V	-1		1	μA
Q _C	Charge injection	V _{GEN} = 0, R _{GEN} = 0,	C _L = 0.1 nF, see Figure 26	25°C	2.5 V		1		рС
$\begin{matrix} C_{NC(OFF)}, \\ C_{NO(OFF)} \end{matrix}$	NC, NO OFF capacitance	V_{NC} or $V_{NO} = V_{+}$ or GND,	Switch OFF, see Figure 20	25°C	2.5 V		3		pF
C _{COM(OFF)}	COM OFF capacitance	$V_{COM} = V_{+}$ or GND,	Switch OFF, see Figure 20	25°C	2.5 V		9		pF
C _{NC(ON)} , C _{NO(ON)}	NC, NO ON capacitance	V_{NC} or $V_{NO} = V_{+}$ or GND,	Switch ON, see Figure 20	25°C	2.5 V		16		pF
C _{COM(ON)}	COM ON capacitance	$V_{COM} = V_{+}$ or GND,	Switch ON, see Figure 20	25°C	2.5 V		16		pF
C _I	Digital input capacitance	$V_1 = V_+ \text{ or GND},$	See Figure 20	25°C	2.5 V		3		pF
BW	Bandwidth	$R_L = 50 \Omega$,	Switch ON, see Figure 22	25°C	2.5 V		300		MHz
O _{ISO}	OFF isolation	$R_L = 50 \Omega$, f = 10 MHz,	Switch OFF, see Figure 23	25°C	2.5 V		-48		dB
X _{TALK}	Crosstalk	$R_L = 50 \Omega$, f = 10 MHz,	Switch ON, see Figure 24	25°C	2.5 V		-48		dB
X _{TALK(ADJ)}	Crosstalk adjacent	$R_L = 50 \Omega$, f = 10 MHz,	Switch ON, see Figure 25	25°C	3.3 V		-81		dB
THD	Total harmonic distortion	$R_L = 600 \Omega,$ $C_L = 50 pF,$	f = 20 Hz to 20 kHz, see Figure 27	25°C	2.5 V		0.33%		
	Positivo aupply aurrent	V = V or CND	Switch ON or OFF	25°C	2.7 V		2.5	7	
I ₊	Positive supply current	$V_I = V_+ \text{ or GND},$	Switch ON OF OFF	Full	2.7 V			10	μA

6.7 Electrical Characteristics for 2.1-V Supply

 $V_{+} = 2.00 \text{ V}$ to 2.20 V, $T_{A} = -40^{\circ}\text{C}$ to 85°C (unless otherwise noted)⁽¹⁾

	, A	,					
	PARAMETER	TEST CONDITIONS	TA	V ₊	MIN	TYP MAX	UNIT
V_{IH}	Input logic high		Full		1.2	4.3	V
V_{IL}	Input logic low		Full		0	0.5	V

⁽¹⁾ The algebraic convention is used in this data sheet; the most negative value is shown in the minimum column.

6.8 Electrical Characteristics for 1.8-V Supply

 $V_{+} = 1.65 \text{ V}$ to 1.95 V, $T_{A} = -40 ^{\circ}\text{C}$ to 85 $^{\circ}\text{C}$ (unless otherwise noted) $^{(1)}$

PARA	METER	TEST C	ONDITIONS	T _A	V ₊	MIN	TYP	MAX	UNIT
V _{COM} , V _{NC} , V _{NO}	Analog signal range					0		V ₊	V
_	ON-state	$0 \le (V_{NC} \text{ or } V_{NO}) \le V_+,$	Switch ON,	25°C	1.65 V		5.5	17	Ω
r _{on}	resistance	$I_{COM} = -32 \text{ mA},$	see Figure 17	Full	1.00 V			32	12
	ON-state			25°C			0.3	1	
Δr_{on}	resistance match between channels	V_{NC} or $V_{NO} = 1.5 \text{ V}$, $I_{COM} = -32 \text{ mA}$,	Switch ON, see Figure 17	Full	1.65 V			1.2	Ω
	ON-state	$0 \le (V_{NC} \text{ or } V_{NO}) \le V_+,$	Switch ON.	25°C			2.7	5.5	
r _{on(flat)}	resistance flatness $I_{COM} = -32 \text{ mA},$		see Figure 17	Full	1.65 V			7.3	Ω

Product Folder Links: TS3A5018

(1) The algebraic convention is used in this data sheet; the most negative value is shown in the minimum column.



Electrical Characteristics for 1.8-V Supply (continued)

 V_{+} = 1.65 V to 1.95 V, T_{A} = -40°C to 85°C (unless otherwise noted)⁽¹⁾

P/	ARAMETER	TEST COM	NDITIONS	T _A	V ₊	MIN	TYP	MAX	UNIT
		V_{NC} or $V_{NO} = 0.3 \text{ V}$, $V_{COM} = 1.65 \text{ V}$,		25°C		-0.25	0.03	0.25	
I _{NC(OFF)} ,	NC, NO OFF leakage	or V _{NC} or V _{NO} = 1.65V, V _{COM} = 0.3 V,	Switch OFF, see Figure 18	Full	1.95 V	-4.5		4.5	μA
I _{NO(OFF)}	current	V_{NC} or $V_{NO} = 1.95 \text{ V to 0 V}$,		25°C		-0.4	0.01	0.4	μΑ
		or V_{NC} or V_{NO} = 0 V to 1.95 V, V_{COM} = 1.95 V to 0 V,	Switch OFF, see Figure 18	Full	0 V	-6.5		6.5	
		$V_{COM} = 1.65 \text{ V},$		25°C		-0.4	0.02	0.4	
	COM OFF leakage	V_{NC} or $V_{NO} = 0.3V$, or $V_{COM} = 0.3 V$, V_{NC} or $V_{NO} = 1.65V$,	Switch OFF, see Figure 18	Full	1.95 V	-0.9		0.9	μA
I _{COM(OFF)}	current	$V_{COM} = 0 \text{ V to } 1.95 \text{ V},$		25°C		-0.4	0.02	0.4	μΑ
		V_{NC} or $V_{NO} = 1.95$ V to 0 V, or $V_{COM} = 1.95$ V to 0, V_{NC} or $V_{NO} = 0$ to 1.95 V,	Switch OFF, see Figure 18	Full	0 V	-4.5		4.5	
		V_{NC} or $V_{NO} = 0.3 \text{ V}$,		25°C		-2.	0.02	2	
I _{NC(ON)} , I _{NO(ON)}	NC, NO ON leakage current	$V_{COM} = Open,$ or V_{NC} or $V_{NO} = 1.65 V,$ $V_{COM} = Open,$	Switch ON, see Figure 19	Full	1.95 V	-2	0.02	2	μΑ
		$V_{COM} = 0.3 \text{ V},$		25°C		-4.5		4.5	
I _{COM(ON)}	COM ON leakage current	V_{NC} or V_{NO} = Open, or V_{COM} = 1.65 V, V_{NC} or V_{NO} = Open,	Switch ON, see Figure 19	Full	1.95 V				μΑ
V _{IH}	Input logic high	V _I = V ₊ or GND		Full	1.95 V	1		3.6	V
V _{IL}	Input logic low			Full	1.95 V	0		0.4	V
	Input leakage	$V_1 = V_+ \text{ or } 0$		25°C	4.05.V	-0.1	0.01	0.1	
I _{IH} , I _{IL}	current	v ₁ = v ₊ 01 0		Full	1.95 V	-2.1		2.1	μA

6.9 Switching Characteristics for 3.3-V Supply

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	Т	EST CONDITIONS	T _A	V ₊	MIN	TYP	MAX	UNIT
		V - 2 V	C - 25 pE	25°C	3.3 V	2.5	3.5	8	
t _{ON}	Turnon time	$V_{COM} = 2 V,$ $R_L = 300 \Omega,$	$C_L = 35 \text{ pF},$ see Figure 21	Full	3 V to 3.6 V	2.5		9	ns
		V 2V	C 25 pC	25°C	3.3 V	0.5	2	6.5	
t _{OFF}	Turnoff time $V_{COM} = 2 \text{ V},$ $R_L = 300 \Omega,$	$R_L = 300 \Omega$	C _L = 35 pF, see Figure 21		3 V to 3.6 V	0.5		7	ns

6.10 Switching Characteristics for 2.5-V Supply

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TES	T CONDITIONS	TA	V ₊	MIN	TYP	MAX	UNIT
		\/ _ 1 5 \/	C - 25 nE	25°C	2.5 V	2.5	5	9.5	
t _{ON}	Turnon time	$V_{COM} = 1.5 \text{ V},$ $R_L = 300 \Omega,$	C _L = 35 pF, see Figure 21	Full	2.3 V to 2.7 V	2.5		10.5	ns
		\/ _1 F \/	C - 25 nE	25°C	2.5 V	0.5	3	7.5	
t _{OFF}	Turnoff time	$V_{COM} = 1.5 \text{ V},$ $R_L = 300 \Omega,$	C _L = 35 pF, see Figure 21	Full	2.3 V to 2.7 V	0.5		9	ns



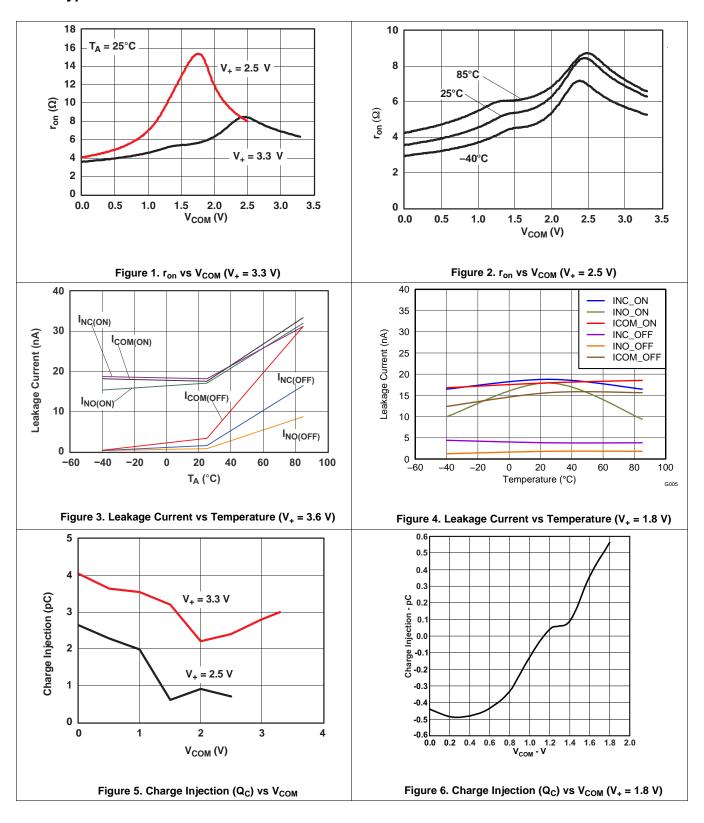
6.11 Switching Characteristics for 1.8-V Supply

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST	CONDITIONS	T _A	V ₊	MIN	TYP	MAX	UNIT
				25°C	1.8 V		14.1	49.3	
t _{ON}	Turnon time	$V_{COM} = V_+,$ $R_L = 50 \Omega,$	C _L = 35 pF, see Figure 21	Full	1.65 V to 1.95 V		49.3	56.7	ns
				25°C	1.8 V		16.1	26.5	
t _{OFF}	Turnoff time	$V_{COM} = V_+,$ $R_L = 50 \Omega,$	C _L = 35 pF, see Figure 21		1.65 V to 1.95 V			31.2	ns
				25°C	1.8 V	5.3	18.4	58	
t _{BBM}	Break-before- make time	$V_{NC} = V_{NO} = V_{+}/2,$ $R_{L} = 50 \Omega,$	2, C _L = 35 pF, see Figure 21		1.65 V to 1.95 V			58	ns

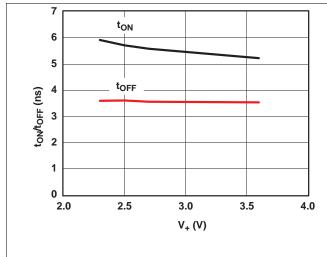
TEXAS INSTRUMENTS

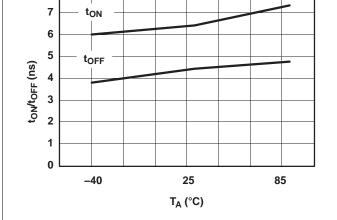
6.12 Typical Characteristics

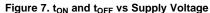




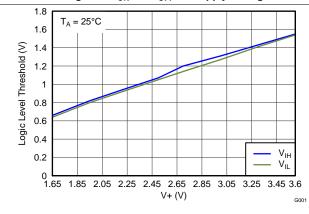
Typical Characteristics (continued)











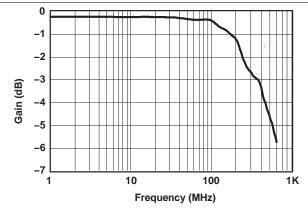
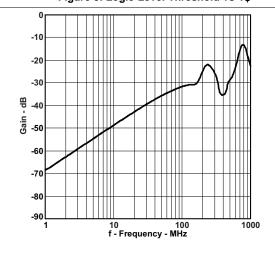


Figure 9. Logic-Level Threshold vs V₊

Figure 10. Gain vs Frequency Bandwidth $(V_{+} = 3.3 \text{ V})$



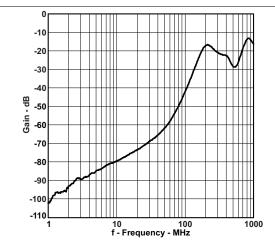


Figure 11. OFF Isolation vs Frequency (V₊ = 1.8 V)

Figure 12. Crosstalk Adjacent vs Frequency (V₊ = 1.8 V)

TEXAS INSTRUMENTS

Typical Characteristics (continued)

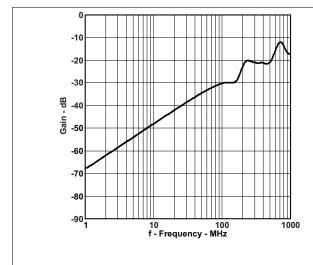


Figure 13. Crosstalk vs Frequency (V₊ = 1.8 V)

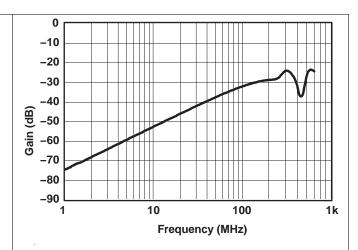


Figure 14. OFF Isolation vs Frequency $(V_+ = 3.3 \text{ V})$

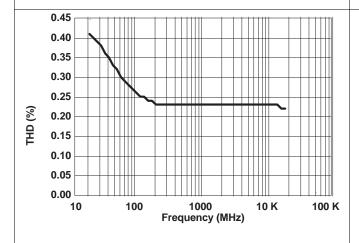


Figure 15. Total Harmonic Distortion vs Frequency

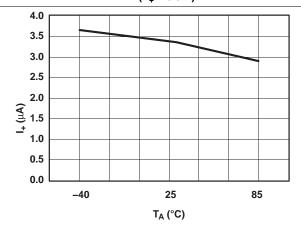


Figure 16. Power-Supply Current vs Temperature $(V_+ = 3.3 \text{ V})$

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7 Parameter Measurement Information

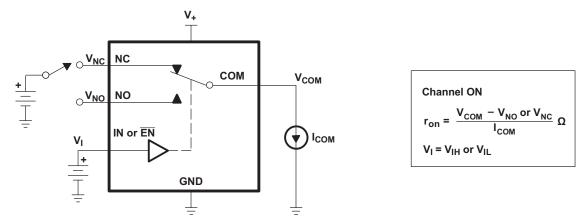


Figure 17. ON-State Resistance (ron)

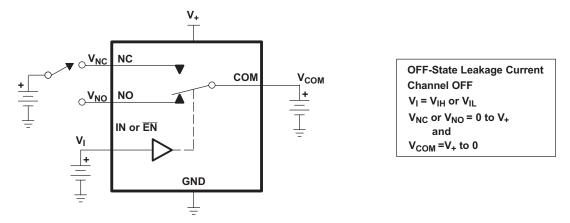


Figure 18. OFF-State Leakage Current ($I_{COM(OFF)}$, $I_{NC(OFF)}$, $I_{NO(OFF)}$)

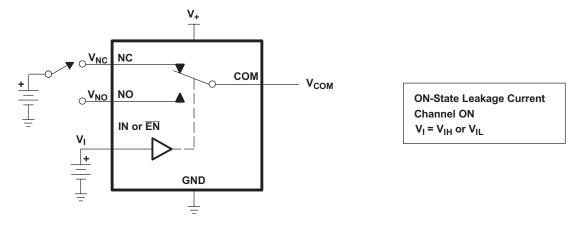


Figure 19. ON-State Leakage Current ($I_{COM(ON)}$, $I_{NC(ON)}$)



Parameter Measurement Information (continued)

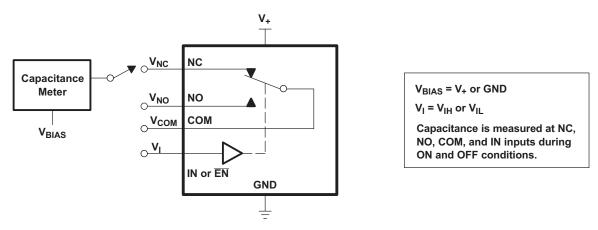
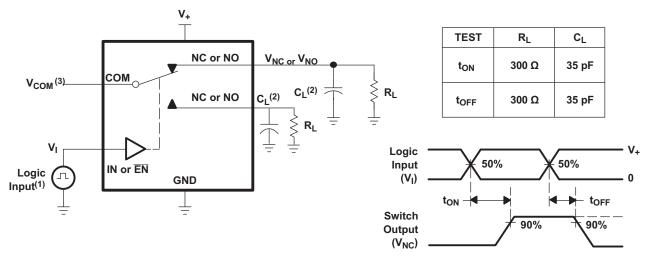


Figure 20. Capacitance (C_I, $C_{COM(OFF)}$, $C_{COM(ON)}$, $C_{NC(OFF)}$, $C_{NC(ON)}$)



- (1) All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_r < 5 \text{ ns}$, $t_f < 5 \text{ ns}$.
- (2) C_L includes probe and jig capacitance.
- (3) See Electrical Characteristics for V_{COM}.

Figure 21. Turnon (t_{ON}) and Turnoff Time (t_{OFF})

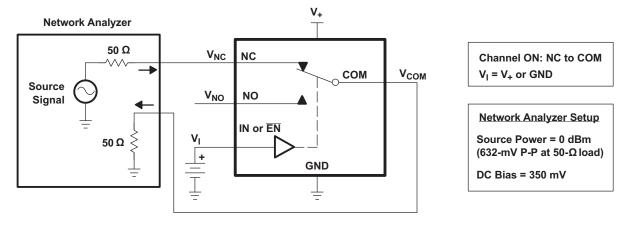
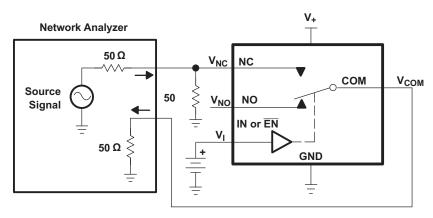


Figure 22. Bandwidth (BW)

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Parameter Measurement Information (continued)

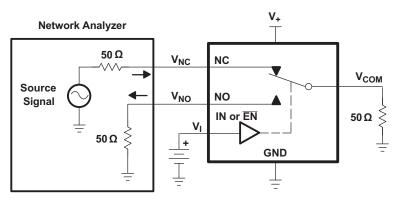


Channel OFF: NC to COM $V_I = V_+$ or GND

Network Analyzer Setup

Source Power = 0 dBm (632-mV P-P at 50-Ωload) DC Bias = 350 mV

Figure 23. OFF Isolation (O_{ISO})

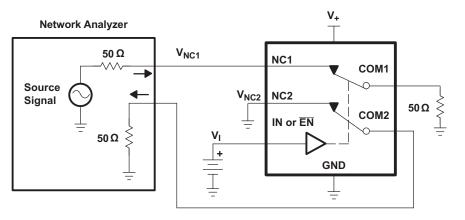


Channel ON: NC to COM
Channel OFF: NO to COM
V_I = V₊ or GND

Network Analyzer Setup

Source Power = 0 dBm (632-mV P-P at $50-\Omega \log d$) DC Bias = 350 mV

Figure 24. Crosstalk (X_{TALK})



Channel ON: NC to COM

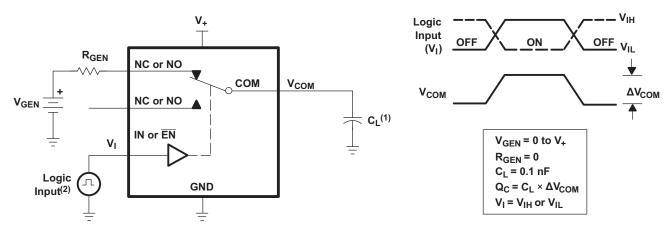
Network Analyzer Setup

Source Power = 0 dBm (632 mV P-P at 50Ω load) DC Bias = 350 mV

Figure 25. Crosstalk Adjacent

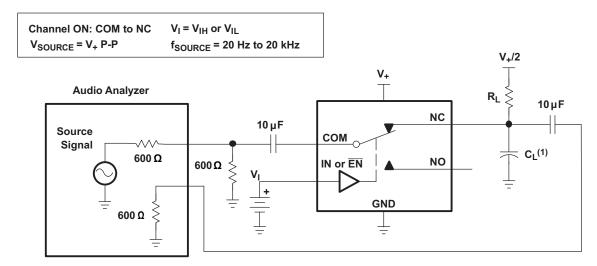


Parameter Measurement Information (continued)



- (1) C_L includes probe and jig capacitance.
- (2) All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_r < 5 \text{ ns}$, $t_f < 5 \text{ ns}$.

Figure 26. Charge Injection (Q_C)



(1) C_L includes probe and jig capacitance.

Figure 27. Total Harmonic Distortion (THD)



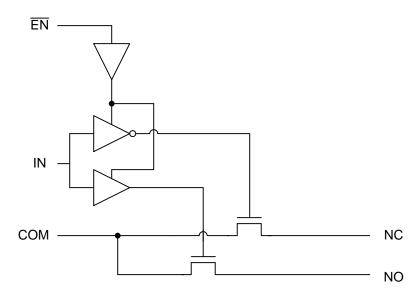
8 Detailed Description

8.1 Overview

The TS3A5018 is a quad single-pole-double-throw (SPDT) solid-state analog switch. The TS3A5018, like all analog switches, is bidirectional. When powered on, each COM pin is connected to its respective NC pin. For this device, NC stands for *normally closed* and NO stands for *normally open*. The switch is enabled when EN is low. If IN is also low, COM is connected to NC. If IN is high, COM is connected to NO.

The TS3A5018 is a break-before-make switch. This means that during switching, a connection is broken before a new connection is established. The NC and NO pins are never connected to each other.

8.2 Functional Block Diagram (Each Switch)



8.3 Feature Description

The low ON-state resistance, ON-state resistance matching, and charge injection in the TS3A5018 make this switch an excellent choice for analog signals that require minimal distortion. In addition, the low THD allows audio signals to be preserved more clearly as they pass through the device.

The 1.8-V to 3.6-V operation allows compatibility with more logic levels, and the bidirectional I/Os can pass analog signals from 0 V to V_{+} with low distortion.

8.4 Device Functional Modes

Table 1. Function Table

EN	IN	NO TO COM, COM TO NO	NC TO COM, COM TO NC
L	L	OFF	ON
L	Н	ON	OFF
Н	Х	OFF	OFF

9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The TS3A5018 can be used in a variety of customer systems. The TS3A5018 can be used anywhere multiple analog or digital signals must be selected to pass across a single line.

9.2 Typical Application

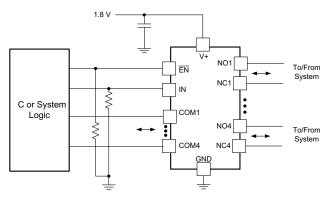


Figure 28. System Schematic for TS3A5018

9.2.1 Design Requirements

In this particular application, V_+ was 1.8 V, although V_+ is allowed to be any voltage specified in *Recommended Operating Conditions*. A decoupling capacitor is recommended on the V+ pin. See *Power Supply Recommendations* for more details.

9.2.2 Detailed Design Procedure

In this application, $\overline{\text{EN}}$ and IN are, by default, pulled low to GND. Choose these resistor sizes based on the current driving strength of the GPIO, the desired power consumption, and the switching frequency (if applicable). If the GPIO is open-drain, use pullup resistors instead.

9.2.3 Application Curve

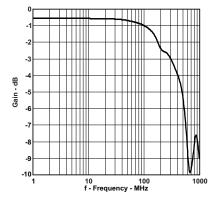


Figure 29. Gain vs Frequency Bandwidth ($V_{+} = 1.8 \text{ V}$)



10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*.

Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, a 0.1- μF bypass capacitor is recommended. If there are multiple pins labeled V_{CC} , then a 0.01- μF or 0.022- μF capacitor is recommended for each V_{CC} because the VCC pins will be tied together internally. For devices with dual supply pins operating at different voltages, for example V_{CC} and V_{DD} , a 0.1- μF bypass capacitor is recommended for each supply pin. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. 0.1- μF and 1- μF capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

11 Layout

11.1 Layout Guidelines

Reflections and matching are closely related to loop antenna theory, but different enough to warrant their own discussion. When a PCB trace turns a corner at a 90° angle, a reflection can occur. This is primarily due to the change of width of the trace. At the apex of the turn, the trace width is increased to 1.414 times its width. This upsets the transmission line characteristics, especially the distributed capacitance and self–inductance of the trace — resulting in the reflection. It is a given that not all PCB traces can be straight, and so they will have to turn corners. Figure 30 shows progressively better techniques of rounding corners. Only the last example maintains constant trace width and minimizes reflections.

Unused switch I/Os, such as NO, NC, and COM, can be left floating or tied to GND. However, the IN and $\overline{\text{EN}}$ pins must be driven high or low. Due to partial transistor turnon when control inputs are at threshold levels, floating control inputs can cause increased I_{CC} or unknown switch selection states.

11.2 Layout Example

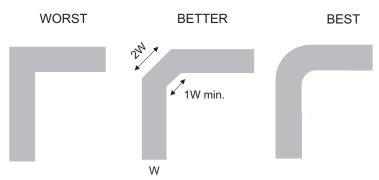


Figure 30. Trace Example



12 Device and Documentation Support

12.1 Device Support

12.1.1 Device Nomenclature

Table 2. Parameter Description

No(OM) (COM) open Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the OFF state	SYMBOL	DESCRIPTION
V _{NO} Voltage at NO for Resistance between COM and NC or NO ports when the channel is ON Difference of r _{con} between channels in a specific device Condition	V _{COM}	Voltage at COM
Fon Resistance between COM and NC or NO ports when the channel is ON Δron Difference of ron between channels in a specific device Fon(tito) Difference between the maximum and minimum value of ron in a channel over the specified range of conditions No(tito) N	V _{NC}	Voltage at NC
Difference of r _{an} between channels in a specific device r _{on(flat)} Difference between the maximum and minimum value of r _{on} in a channel over the specified range of conditions INC(OFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) open Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the ON state and the output (COM) open Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the OFF state Leakage current measured at the COM port, with the corresponding channel (NO to COM) in the OFF state Leakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the OFF state Leakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the OFF state Leakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the OFF state V ₁ Maximum input voltage for logic low for the control input (IN, EN) V ₁ Voltage at the control input (IN, EN) V ₂ Voltage at the control input (IN, EN) 1 _{ON} 1 _O	V _{NO}	Voltage at NO
Incompton Difference between the maximum and minimum value of ron in a channel over the specified range of conditions $ N_{COFF} $ Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state $ N_{COMF} $ Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the OFF state Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the OFF state $ N_{COMF} $ Leakage current measured at the COM port, with the corresponding channel (NO to COM) in the OFF state Leakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the OFF state Leakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the OFF state Leakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the OFF state Leakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the OFF state Leakage current measured the COM port, with the corresponding channel (COM to NC or NO) in the OFF state Leakage current measured the control input (IN, EN) Vil. Maximum input voltage for logic low for the control input (IN, EN) Voltage at the control input (IN, EN) Leakage current measured at the control input (IN, EN) Turnon time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output NC or NO) signal when the switch is turning OFF. Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC or NO) output. This is measured in columb (C) and measured by the total charge induced due to switching of the control input (IN, EN) Charge injection, Q = C x AVCons. Q is the load capacitance and AVCooms is the change in analog output voltage. CNCOMION Capacitance at the NC port w	r _{on}	Resistance between COM and NC or NO ports when the channel is ON
Inc(OFF) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state	Δr_{on}	Difference of r _{on} between channels in a specific device
Inci(ON) Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) open	r _{on(flat)}	Difference between the maximum and minimum value of ron in a channel over the specified range of conditions
No(OM) (COM) open Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the OFF state	I _{NC(OFF)}	Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the OFF state
I _{NO(ON)} Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the ON state and the outpin (COM) open	I _{NC(ON)}	Leakage current measured at the NC port, with the corresponding channel (NC to COM) in the ON state and the output (COM) open
No(OM) (COM) open Leakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the OFF state	I _{NO(OFF)}	Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the OFF state
Leakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the ON state and output (NC or NO) open V _{IH} Minimum input voltage for logic high for the control input (IN, EN) V _{IL} Maximum input voltage for logic low for the control input (IN, EN) V _{IL} Maximum input voltage for logic low for the control input (IN, EN) I _{IH} , I _{IL} Leakage current measured at the control input (IN, EN) Turnon time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output NC or NO) signal when the switch is turning ON. Turnoff time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output NC or NO) signal when the switch is turning OFF. Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC or NO) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input Charge injection, Q _C = C _L x \(\Delta \text{VOM}\). C _L is the load capacitance and \(\Delta \text{VOM}\) is the change in analog output voltage. C _{NC(OFF)} Capacitance at the NC port when the corresponding channel (NC to COM) is OFF C _{NC(ON)} Capacitance at the NC port when the corresponding channel (NC to COM) is OFF C _{NC(ON)} Capacitance at the NC port when the corresponding channel (NO to COM) is ON C _{COM(OFF)} Capacitance at the NC port when the corresponding channel (NO to COM) is ON C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (NO to COM) is ON C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (NO to COM) is ON C ₁ Capacitance at the COM port when the corresponding channel (NO to COM) is ON C ₂ Capacitance at the COM port when the corresponding channel (NO to COM) is ON C ₃ Capacitance at the COM port when the corresponding channel (NO to	I _{NO(ON)}	Leakage current measured at the NO port, with the corresponding channel (NO to COM) in the ON state and the output (COM) open
V _{IH} Minimum input voltage for logic high for the control input (IN, EN) V _{IL} Maximum input voltage for logic low for the control input (IN, EN) V _I Voltage at the control input (IN, EN) I _{IH} , I _{IL} Leakage current measured at the control input (IN, EN) toN Turnon time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output NC or NO) signal when the switch is turning ON. Turnoff time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output NC or NO) signal when the switch is turning ON. Q _C Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC or NO) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input (Charge injection, Q _C = C _L × ΔV _{COM} , C _L is the load capacitance and ΔV _{COM} is the change in analog output voltage. C _{NC(OFF)} Capacitance at the NC port when the corresponding channel (NC to COM) is OFF C _{NC(ON)} Capacitance at the NC port when the corresponding channel (NC to COM) is ON C _{COM(OFF)} Capacitance at the NC port when the corresponding channel (NO to COM) is ON C _{COM(OFF)} Capacitance at the NC port when the corresponding channel (NO to COM) is ON C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (COM to NC) is OFF C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (COM to NC) is ON C _C Capacitance at the COM port when the corresponding channel (COM to NC) is ON C ₁ Capacitance at the COM port when the corresponding channel (COM to NC) is ON C ₁ Capacitance at the COM port when the corresponding channel (COM to NC) is ON C ₁ Capacitance at the COM port when the corresponding channel (COM to NC) is ON C ₁ Capacitance at the COM port when the corresponding channel (COM to NC) is ON C ₂	I _{COM(OFF)}	Leakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the OFF state
V _{IL} Maximum input voltage for logic low for the control input (IN, EN) V _I Voltage at the control input (IN, EN) I _{IH} , I _{IL} Leakage current measured at the control input (IN, EN) toN Turnon time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output NC or NO) signal when the switch is turning ON. toFF Turnoff time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output NC or NO) signal when the switch is turning OFF. Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC or NO) output. This is measured in coulomb (C) and measured by the total carge induced due to switching of the control input Charge injection, Q _C = C _L × ΔV _{COM} , C _L is the load capacitance and ΔV _{COM} is the change in analog output voltage. C _{NC(OFF)} Capacitance at the NC port when the corresponding channel (NC to COM) is OFF C _{NC(ON)} Capacitance at the NC port when the corresponding channel (NC to COM) is ON C _{COM(OFF)} Capacitance at the NC port when the corresponding channel (NO to COM) is OFF C _{COM(OFF)} Capacitance at the NC port when the corresponding channel (NO to COM) is OFF C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (COM to NC) is OFF C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (COM to NC) is ON C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (COM to NC) is ON C _{COM(ON)} Capacitance of control input (IN, EN) OFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM) in the OFF state. Crosstalk is a measurement of unwanted signal coupling from an ON channel to an off channel (NC1 to NC2). Th measured in a specific frequency and in dB. Bandwidth o	I _{COM(ON)}	Leakage current measured at the COM port, with the corresponding channel (COM to NC or NO) in the ON state and the output (NC or NO) open
V _I Voltage at the control input (IN, EN) I _{IH} , I _{IL} Leakage current measured at the control input (IN, EN) toN Turnon time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output NC or NO) signal when the switch is turning ON. toFF Turnoff time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output (NC or NO) signal when the switch is turning OFF. Q _C Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC or NO) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input Charge injection, Q _C = C _L × ΔV _{COM} , C _L is the load capacitance and ΔV _{COM} is the change in analog output voltage. C _{NC(OFF)} Capacitance at the NC port when the corresponding channel (NC to COM) is OFF C _{NC(ON)} Capacitance at the NC port when the corresponding channel (NO to COM) is OFF C _{NO(ON)} Capacitance at the NC port when the corresponding channel (NO to COM) is OFF C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (NO to COM) is ON C _{COM(ON)} Capacitance at the COM port when the corresponding channel (NO to COM) is ON C _{COM(ON)} Capacitance at the COM port when the corresponding channel (NO to COM) is ON	V _{IH}	Minimum input voltage for logic high for the control input (IN, EN)
ton	V _{IL}	Maximum input voltage for logic low for the control input (IN, EN)
Turnon time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output NC or NO) signal when the switch is turning ON. Turnoff time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output (NC or NO) signal when the switch is turning OFF. Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC or NO) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input Charge injection, Q _C = C _L × ΔV _{COM} , C _L is the load capacitance and ΔV _{COM} is the change in analog output voltage. CNC(ON) Capacitance at the NC port when the corresponding channel (NC to COM) is OFF CNC(ON) Capacitance at the NC port when the corresponding channel (NC to COM) is OFF CNO(ON) Capacitance at the NC port when the corresponding channel (NO to COM) is OFF CCOM(OFF) Capacitance at the NC port when the corresponding channel (NO to COM) is OFF CCOM(OFF) Capacitance at the COM port when the corresponding channel (COM to NC) is OFF CCOM(OFF) Capacitance at the COM port when the corresponding channel (COM to NC) is OFF CCOM(ON) Capacitance at the COM port when the corresponding channel (COM to NC) is ON C1 Capacitance at the COM port when the corresponding channel (COM to NC) is ON C3 CAPACITANCE	V _I	Voltage at the control input (IN, $\overline{\text{EN}}$)
delay between the digital control (IN) signal and analog output NC or NO) signal when the switch is turning ON. Turnoff time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output (NC or NO) signal when the switch is turning OFF. Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC or NO) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input Charge injection, Q _C = C _L × ΔV _{COM} , C _L is the load capacitance and ΔV _{COM} is the change in analog output voltage. C _{NC(OFF)} Capacitance at the NC port when the corresponding channel (NC to COM) is OFF C _{NC(ON)} Capacitance at the NC port when the corresponding channel (NO to COM) is ON C _{NO(OFF)} Capacitance at the NC port when the corresponding channel (NO to COM) is OFF C _{NO(ON)} Capacitance at the NC port when the corresponding channel (NO to COM) is ON C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (COM to NC) is OFF C _{COM(ON)} Capacitance at the COM port when the corresponding channel (COM to NC) is OFF C _{COM(ON)} Capacitance at the COM port when the corresponding channel (COM to NC) is ON C ₁ Capacitance of control input (IN, EN) O ₁ OFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM) in the OFF state. Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NO1). Adjac crosstalk is a measurement of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2). The measured in a specific frequency and in dB. ThD Bandwidth of the switch. This is the frequency in which the gain of an ON channel is –3 dB below the DC gain. Total harmonic distortion describes the signal distortion caused by the analog switch. This is	I _{IH} , I _{IL}	Leakage current measured at the control input (IN, EN)
delay between the digital control (IN) signal and analog output (NC or NO) signal when the switch is turning OFF. Charge injection is a measurement of unwanted signal coupling from the control (IN) input to the analog (NC or NO) output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input. Charge injection, Q _C = C _L × ΔV _{COM} , C _L is the load capacitance and ΔV _{COM} is the change in analog output voltage. C _{NC(OFF)} Capacitance at the NC port when the corresponding channel (NC to COM) is OFF C _{NC(ON)} Capacitance at the NC port when the corresponding channel (NC to COM) is ON C _{NO(OFF)} Capacitance at the NC port when the corresponding channel (NO to COM) is OFF C _{NO(ON)} Capacitance at the NC port when the corresponding channel (NO to COM) is ON C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (COM to NC) is OFF C _{COM(ON)} Capacitance at the COM port when the corresponding channel (COM to NC) is ON C _I Capacitance of control input (IN, EN) O _{ISO} OFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM) in the OFF state. Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NC1). Adjac crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2). The measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is –3 dB below the DC gain. Total harmonic distortion describes the signal distortion caused by the analog switch. This is defined as the ratio of roc mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.	t _{ON}	Turnon time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output NC or NO) signal when the switch is turning ON.
QC output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input Charge injection, Q _C = C _L x ΔV _{COM} , C _L is the load capacitance and ΔV _{COM} is the change in analog output voltage. C _{NC(OFF)} Capacitance at the NC port when the corresponding channel (NC to COM) is OFF C _{NC(ON)} Capacitance at the NC port when the corresponding channel (NO to COM) is OFF C _{NO(OFF)} Capacitance at the NC port when the corresponding channel (NO to COM) is ON C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (COM to NC) is OFF C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (COM to NC) is ON C _I Capacitance at the COM port when the corresponding channel (COM to NC) is ON C _I Capacitance of control input (IN, EN) O _{ISO} OFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM) in the OFF state. X _{TALK} Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NO1). Adjac crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2). The measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is –3 dB below the DC gain. THD Total harmonic distortion	t _{OFF}	Turnoff time for the switch. This parameter is measured under the specified range of conditions and by the propagation delay between the digital control (IN) signal and analog output (NC or NO) signal when the switch is turning OFF.
C _{NC(ON)} Capacitance at the NC port when the corresponding channel (NC to COM) is ON C _{NO(OFF)} Capacitance at the NC port when the corresponding channel (NO to COM) is OFF C _{NO(ON)} Capacitance at the NC port when the corresponding channel (NO to COM) is ON C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (COM to NC) is OFF C _{COM(ON)} Capacitance at the COM port when the corresponding channel (COM to NC) is ON C _I Capacitance at the COM port when the corresponding channel (COM to NC) is ON C _I Capacitance of control input (IN, EN) O _{ISO} OFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM) in the OFF state. Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NO1). Adjact crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2). The measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is –3 dB below the DC gain. Total harmonic distortion describes the signal distortion caused by the analog switch. This is defined as the ratio of roc mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.	Q _C	output. This is measured in coulomb (C) and measured by the total charge induced due to switching of the control input.
C _{NC(ON)} Capacitance at the NC port when the corresponding channel (NC to COM) is ON C _{NO(OFF)} Capacitance at the NC port when the corresponding channel (NO to COM) is OFF C _{NO(ON)} Capacitance at the NC port when the corresponding channel (NO to COM) is ON C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (COM to NC) is OFF C _{COM(ON)} Capacitance at the COM port when the corresponding channel (COM to NC) is ON C _I Capacitance of control input (IN, EN) O _{ISO} OFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM) in the OFF state. Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NO1). Adjact crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2). The measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is –3 dB below the DC gain. Total harmonic distortion describes the signal distortion caused by the analog switch. This is defined as the ratio of roc mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.	C _{NC(OFF)}	Capacitance at the NC port when the corresponding channel (NC to COM) is OFF
C _{NO(OFF)} Capacitance at the NC port when the corresponding channel (NO to COM) is OFF C _{NO(ON)} Capacitance at the NC port when the corresponding channel (NO to COM) is ON C _{COM(OFF)} Capacitance at the COM port when the corresponding channel (COM to NC) is OFF C _{COM(ON)} Capacitance at the COM port when the corresponding channel (COM to NC) is ON C _I Capacitance of control input (IN, EN) O _{ISO} OFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM) in the OFF state. Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NO1). Adjact crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2). The measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is –3 dB below the DC gain. Total harmonic distortion describes the signal distortion caused by the analog switch. This is defined as the ratio of roc mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.		Capacitance at the NC port when the corresponding channel (NC to COM) is ON
Com(OFF) Capacitance at the COM port when the corresponding channel (COM to NC) is OFF Com(ON) Capacitance at the COM port when the corresponding channel (COM to NC) is ON Capacitance of control input (IN, EN) OFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM) in the OFF state. Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NO1). Adjact crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2). The measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is –3 dB below the DC gain. Total harmonic distortion describes the signal distortion caused by the analog switch. This is defined as the ratio of roce mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.		Capacitance at the NC port when the corresponding channel (NO to COM) is OFF
C _{COM(ON)} Capacitance at the COM port when the corresponding channel (COM to NC) is ON C _I Capacitance of control input (IN, EN) O _{ISO} OFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM) in the OFF state. Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NO1). Adjact crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2). The measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is –3 dB below the DC gain. Total harmonic distortion describes the signal distortion caused by the analog switch. This is defined as the ratio of rock mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.	C _{NO(ON)}	Capacitance at the NC port when the corresponding channel (NO to COM) is ON
C _I Capacitance of control input (IN, EN) O _{ISO} OFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM) in the OFF state. Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NO1). Adjact crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2). The measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is –3 dB below the DC gain. Total harmonic distortion describes the signal distortion caused by the analog switch. This is defined as the ratio of roc mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.	C _{COM(OFF)}	Capacitance at the COM port when the corresponding channel (COM to NC) is OFF
OFF isolation of the switch is a measurement of OFF-state switch impedance. This is measured in dB in a specific frequency, with the corresponding channel (NC to COM) in the OFF state. Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NO1). Adjact crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2). The measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is –3 dB below the DC gain. Total harmonic distortion describes the signal distortion caused by the analog switch. This is defined as the ratio of rock mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.	C _{COM(ON)}	Capacitance at the COM port when the corresponding channel (COM to NC) is ON
frequency, with the corresponding channel (NC to COM) in the OFF state. Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NO1). Adjact crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2). The measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is –3 dB below the DC gain. Total harmonic distortion describes the signal distortion caused by the analog switch. This is defined as the ratio of rock mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.	C _I	Capacitance of control input (IN, EN)
X _{TALK} crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2) .Th measured in a specific frequency and in dB. BW Bandwidth of the switch. This is the frequency in which the gain of an ON channel is -3 dB below the DC gain. Total harmonic distortion describes the signal distortion caused by the analog switch. This is defined as the ratio of roc mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.	O _{ISO}	
Total harmonic distortion describes the signal distortion caused by the analog switch. This is defined as the ratio of roc mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.	X _{TALK}	Crosstalk is a measurement of unwanted signal coupling from an ON channel to an OFF channel (NC1 to NO1). Adjacent crosstalk is a measure of unwanted signal coupling from an ON channel to an adjacent ON channel (NC1 to NC2) .This is measured in a specific frequency and in dB.
THD mean square (RMS) value of the second, third, and higher harmonic to the absolute magnitude of the fundamental harmonic.	BW	Bandwidth of the switch. This is the frequency in which the gain of an ON channel is -3 dB below the DC gain.
Costing power comply content with the control (IN) pig = 1/7 = 2 OND	THD	
$_{1+}$ Static power-supply current with the control (IIV) pin at V_+ or GND	I ₊	Static power-supply current with the control (IN) pin at V ₊ or GND



12.2 Documentation Support

12.2.1 Related Documentation

For related documentation, see the following:

Implications of Slow or Floating CMOS Inputs, SCBA004

12.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.4 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community T's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.5 Trademarks

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

12.6 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

12.7 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.





15-May-2018

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
TS3A5018D	ACTIVE	SOIC	Drawing	16	40	(2) Green (RoHS & no Sb/Br)	(6) CU NIPDAU	(3) Level-1-260C-UNLIM	-40 to 85	(4/5) TS3A5018	Samples
TS3A5018DBQR	ACTIVE	SSOP	DBQ	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	YA018	Samples
TS3A5018DBQRE4	ACTIVE	SSOP	DBQ	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	YA018	Samples
TS3A5018DBQRG4	ACTIVE	SSOP	DBQ	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	YA018	Samples
TS3A5018DE4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS3A5018	Samples
TS3A5018DGVR	ACTIVE	TVSOP	DGV	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	YA018	Samples
TS3A5018DR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS3A5018	Samples
TS3A5018DRE4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS3A5018	Samples
TS3A5018PW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	YA018	Samples
TS3A5018PWG4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	YA018	Samples
TS3A5018PWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	YA018	Samples
TS3A5018PWRE4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	YA018	Samples
TS3A5018RGYR	ACTIVE	VQFN	RGY	16	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	YA018	Samples
TS3A5018RGYRG4	ACTIVE	VQFN	RGY	16	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	YA018	Samples
TS3A5018RSVR	ACTIVE	UQFN	RSV	16	3000	Green (RoHS & no Sb/Br)	CU NIPDAU CU NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	ZUN	Samples

⁽¹⁾ The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.



PACKAGE OPTION ADDENDUM

15-May-2018

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 13-Jun-2018

TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TS3A5018DBQR	SSOP	DBQ	16	2500	330.0	12.5	6.4	5.2	2.1	8.0	12.0	Q1
TS3A5018DGVR	TVSOP	DGV	16	2000	330.0	12.4	6.8	4.0	1.6	8.0	12.0	Q1
TS3A5018DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
TS3A5018PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TS3A5018RGYR	VQFN	RGY	16	3000	330.0	12.4	3.8	4.3	1.5	8.0	12.0	Q1
TS3A5018RSVR	UQFN	RSV	16	3000	180.0	12.4	2.1	2.9	0.75	4.0	12.0	Q1
TS3A5018RSVR	UQFN	RSV	16	3000	177.8	12.4	2.0	2.8	0.7	4.0	12.0	Q1

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TS3A5018DBQR	SSOP	DBQ	16	2500	340.5	338.1	20.6
TS3A5018DGVR	TVSOP	DGV	16	2000	367.0	367.0	35.0
TS3A5018DR	SOIC	D	16	2500	333.2	345.9	28.6
TS3A5018PWR	TSSOP	PW	16	2000	367.0	367.0	35.0
TS3A5018RGYR	VQFN	RGY	16	3000	367.0	367.0	35.0
TS3A5018RSVR	UQFN	RSV	16	3000	203.0	203.0	35.0
TS3A5018RSVR	UQFN	RSV	16	3000	202.0	201.0	28.0

D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



D (R-PDSO-G16)

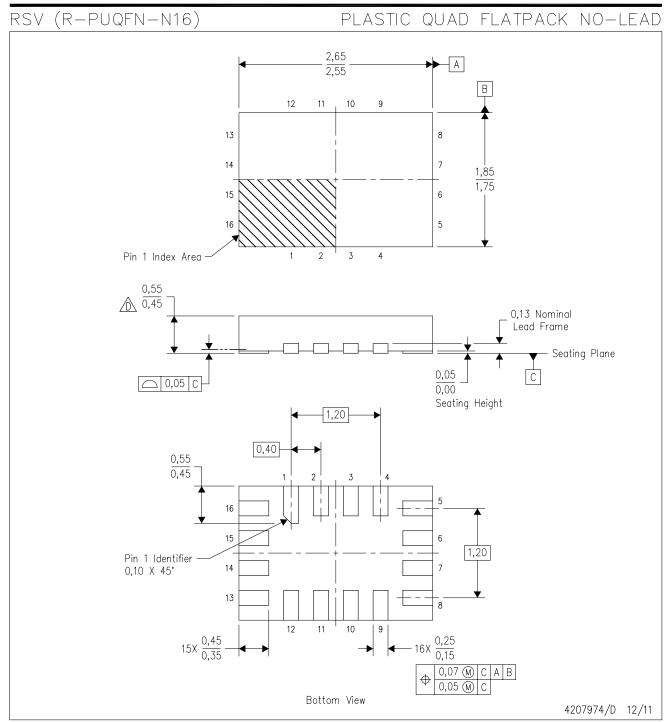
PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.





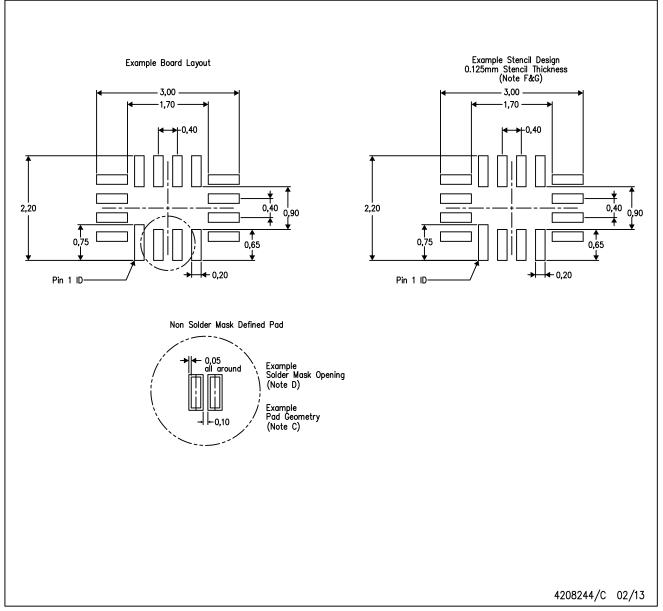
NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) package configuration.
- This package complies to JEDEC MO-288 variation UFHE, except minimum package thickness.



RSV (R-PUQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD



NOTES: A.

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.
- E. Maximum stencil thickness 0,127 mm (5 mils). All linear dimensions are in millimeters.
- F. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- G. Side aperture dimensions over—print land for acceptable area ratio > 0.66. Customer may reduce side aperture dimensions if stencil manufacturing process allows for sufficient release at smaller opening.



DGV (R-PDSO-G**)

24 PINS SHOWN

PLASTIC SMALL-OUTLINE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15 per side.

D. Falls within JEDEC: 24/48 Pins – MO-153 14/16/20/56 Pins – MO-194 PW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153





Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.







NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 inch, per side.
- 4. This dimension does not include interlead flash.5. Reference JEDEC registration MO-137, variation AB.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- Pin 1 identifiers are located on both top and bottom of the package and within the zone indicated. The Pin 1 identifiers are either a molded, marked, or metal feature.
- G. Package complies to JEDEC MO-241 variation BA.



RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

Exposed Thermal Pad Dimensions

4206353-3/P 03/14

NOTE: All linear dimensions are in millimeters



RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat—Pack QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com http://www.ti.com.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



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